

QUERY CONTROL FORM		RTIS USE ONLY	
Application No. <u>09980432</u>	Prepared by <u>ewc</u>	Tracking Number <u>05964381</u>	
Examiner-GAU <u>Nguyen</u>	Date <u>8-10-04</u>	Week Date <u>6-14-04</u>	
<u>2881</u>	No. of queries <u>-2-</u>	IFW	

JACKET

a. Serial No.	f. Foreign Priority	k. Print Claim(s)	<u>p. PTO-1449</u>
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	<u>t. Other</u>

SPECIFICATION

- a. Page Missing
- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
- f. Duplicate Text
- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

MESSAGE

ATTENTION: CHIEF DRAFTSPERSON

1) Drawing numbers are not shown
on drawings of 11-28-01 for
Fig 2 and Fig 23C.

2) PTO-1449 - Please either initial
or line through citations.
see attached copy.

Thank you
ewc

CLAIMS

- a. Claim(s) Missing
- b. Improper Dependency
- c. Duplicate Numbers
- d. Incorrect Numbering
- e. Index Disagrees
- f. Punctuation
- g. Amendments
- h. Bracketing
- i. Missing Text
- j. Duplicate Text
- k. Other

initials

RESPONSE

initials

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. GIVAR7.001APC	APPLICATION NO. 09/880,432
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Givargizov, et al.	
		FILING DATE November 29, 2001	GROUP Unknown

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
	5,742,377	04/21/88	Minne, et al.			
	5,825,122	10/20/88	Givargizov, et al.			
	6,308,734	10/23/01	Givargizov			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	WO 98/42101	12/27/88	PCT				
	WO 99/58925	11/18/99	PCT				

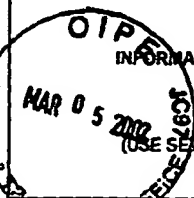
OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

EXAMINER INITIAL	
	C.A. Spindt, et al., <i>Physical properties of thin-film field emission cathodes with molybdenum cones</i> , J. Appl. Phys., 47, pp. 5248-5283 (1976)
	P. Grütter, et al., <i>Batch fabricated sensors for magnetic force microscopy</i> , Appl. Phys. Lett. 57, pp. 1820-1822 (1990)
	D.W. Abraham, et al., <i>Lateral dopant profiling in semiconductors by force microscopy using capacitive detection</i> , J. Vac. Sci. Technol., 89, pp. 703-706 (1991)
	K.L. Lee, et al., <i>Submicron Si trench profiling with an electron-beam fabricated atomic force microscope tip</i> , J. Vac. Sci. Technol., 89, pp. 3352-3568 (1991)
	E.I. Givargizov, <i>Ultrasharp tips for field emission applications prepared by the vapor-liquid-solid growth technique</i> , J. Vac. Sci. Technol., 811, pp. 448-453 (1993)

EXAMINER

DATE CONSIDERED

*EXAMINER: INITIAL IF CITATION CONSIDERED. WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.

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EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
	C.D. Frisbie, et al., <i>Functional group imaging by chemical force microscopy</i> , Science, 265, pp. 2071-2074 (1994)
	V.A. Bykov, et al., <i>New devices and possibilities in a scanning probe microscopy</i> , in: Proc. Russian 1999 Conf. On SPM, Nizhni Novgorod, pp. 132-133 (March 1999)
	J. Browning, <i>Field emission display development and testing</i> , Proc. Of the 8 th Intern. Conf. On Vacuum Microelectronics (Portland, USA), pp. 1-8 (1995)
	Y. Huang, et al., <i>Quantitative two-dimensional dopant profiling of abrupt dopant profiles by cross-sectional scanning capacitance microscopy</i> , J. Vac. Sci. Technol. A14, pp. 1168-1171 (1998)
	J.H. Hafner, et al., <i>Growth of nanotubes for probe microscopy tips</i> , Nature 398, pp. 761-762 (1999)
	P. Leinenbach, et al., <i>Fabrication and characterization of advanced probes for magnetic force microscopy</i> , Appl. Surf. Sci., 144-145, pp. 492-496 (1999)
	L. Abelman, et al., <i>Analysis of the limit of resolution in magnetic force microscopy using EBID tips</i> , a paper presented to Intern. STM Conf., Seoul, Korea, Ext. Abstr., pp. 477-478 (1999)
	V.V. Dremov, et al., <i>An alternative working mode of SPM at surface investigations</i> , in: Proc. Russian 1999 Conf. On SPM, Nizhni Novgorod, pp. 404-410 (March 1999)
	E.I. Givargizov, et al., <i>Whisker probes</i> , Ultramicroscopy 82, pp. 57-61 (2000)

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